

SK8603160L

MOS FET SK8603160L

### For Load-switching / For DC-DC Converter

Silicon N-channel MOS FET

- Features
- Low Drain-source On-state Resistance : RDS(on) typ = 3.3 mΩ (VGS = 4.5 V)
- Halogen-free / RoHS compliant (EU RoHS / UL-94 V-0 / MSL : Level 1 compliant)
- Marking Symbol : 16
- Packaging

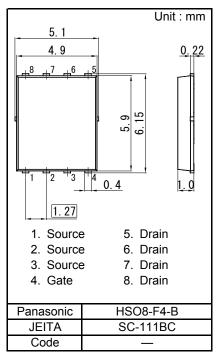
Embossed type (Thermo-compression sealing): 3 000 pcs / reel (standard)

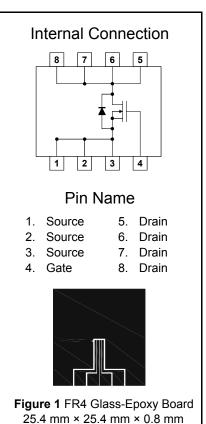
Absolute Maximum Ratings Ta = 25 °C								
Parameter			Symbol	Rating	Unit			
Drain to Source Voltage			VDS	30	V			
Gate to Source Voltage			VGS	±20	v			
	Ta = 25 °C, t = 10 s <sup>*1</sup> Ta = 25 °C, DC <sup>*1</sup> Tc = 25 °C		ID	34				
Drain Current				22	А			
Dialit Curtent				70	A			
	Pulsed	d, Tch < 150 °C <sup>*2</sup>		102				
Total Power			PD	2.8	W			
Dissipation		Tc = 25 °C		28				
Thermal Resistance		Channel to Ambient	Rth(ch-a)	44	°C/W			
	ance	Channel to Case	Rth(ch-c)	4.5	C/W			
Channel Temperature			Tch	150				
Operating ambient temperature			Topr	-40 to +85	°C			
Storage Temperature Range			Tstg	-55 to +150				
Avalanche Current (Single pulse) *3			IAR	17	А			
Avalanche Energy (Single pulse) *3			EAR	36	mJ			

Note \*1 Device mounted on a glass-epoxy board in Figure 1

\*2 Pulse test: Ensure that the channel temperature does not exceed 150 °C

\*3 VDD = 24 V, VGS = 10 to 0 V, L = 0.1 mH, Tch = 25 °C (initial)





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#### ■ Electrical Characteristics Ta = 25 °C ± 3 °C

#### Static Characteristics

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain-source Breakdown Voltage	VDSS	ID = 1 mA, VGS = 0 V	30			V
Zero Gate Voltage Drain Current	IDSS	VDS = 30 V, VGS = 0 V			10	μA
Gate-source Leakage Current	IGSS	VGS = ±16 V, VDS = 0 V			±10	μA
Gate-source Threshold Voltage	Vth	ID = 3.35 mA, VDS = 10 V	1.3		3	V
Drain-source On-state Resistance	RDS(on)1	ID = 17 A, VGS = 10 V		2.5	3.3	mΩ
	RDS(on)2	ID = 17 A, VGS = 4.5 V		3.3	4.3	1115.2

#### **Dynamic Characteristics**

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Input Capacitance	Ciss	VDS = 10 V, VGS = 0 V		2 800	3 920	
Output Capacitance	Coss	f = 1 MHz		330	462	pF
Reverse Transfer Capacitance	Crss			230	368	
Turn-on Delay Time <sup>*1</sup>	td(on)	VDD = 15 V, VGS = 0 to 10 V		13		20
Rise Time <sup>*1</sup>	tr	ID = 17 A		12		ns
Turn-off Delay Time <sup>*1</sup>	td(off)	VDD = 15 V, VGS = 10 to 0 V		52		20
Fall Time <sup>*1</sup>	tf	ID = 17 A		8		ns
Total Gate Charge	Qg	$\sqrt{DD} = 15 \sqrt{\sqrt{CC}} = 0 to 4 5 \sqrt{CC}$		22		
Gate to Source Charge	Qgs	VDD = 15 V, VGS = 0 to 4.5 V ID = 17 A		7		nC
Gate to Drain Charge	Qgd			9		
Gate resistance	rg	f = 5 MHz		1.2	3	Ω

#### Body Diode Characteristic

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Diode Forward Voltage	VSD	IS = 17 A, VGS = 0 V		0.8	1.2	V

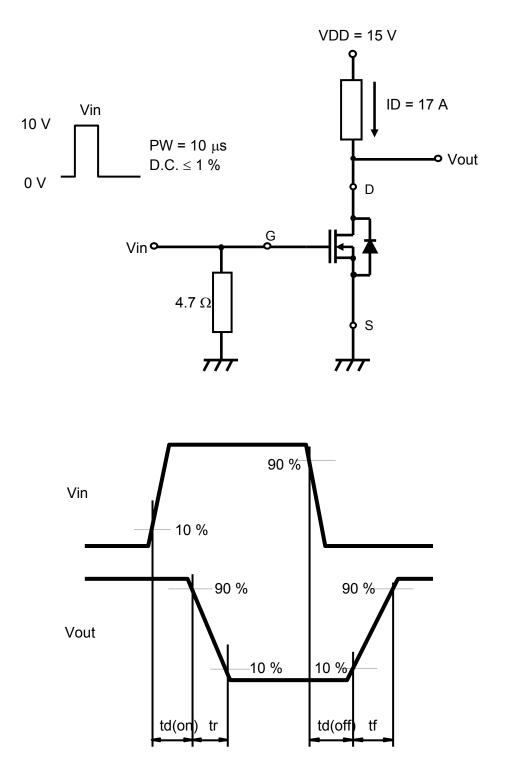
Note: 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 Measuring methods for transistors.

2. \*1 Measurement circuit for Turn-on Delay Time / Rise Time / Turn-off Delay Time / Fall Time

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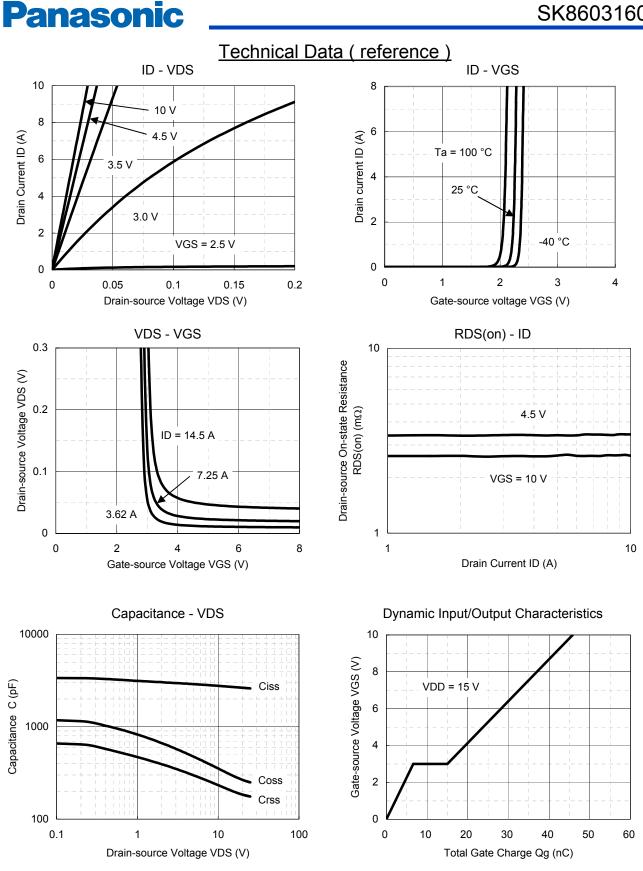


\*1 Measurement circuit for Turn-on Delay Time / Rise Time / Turn-off Delay Time / Fall Time



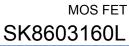
Established : 2012-12-10 Revised : 2013-05-31

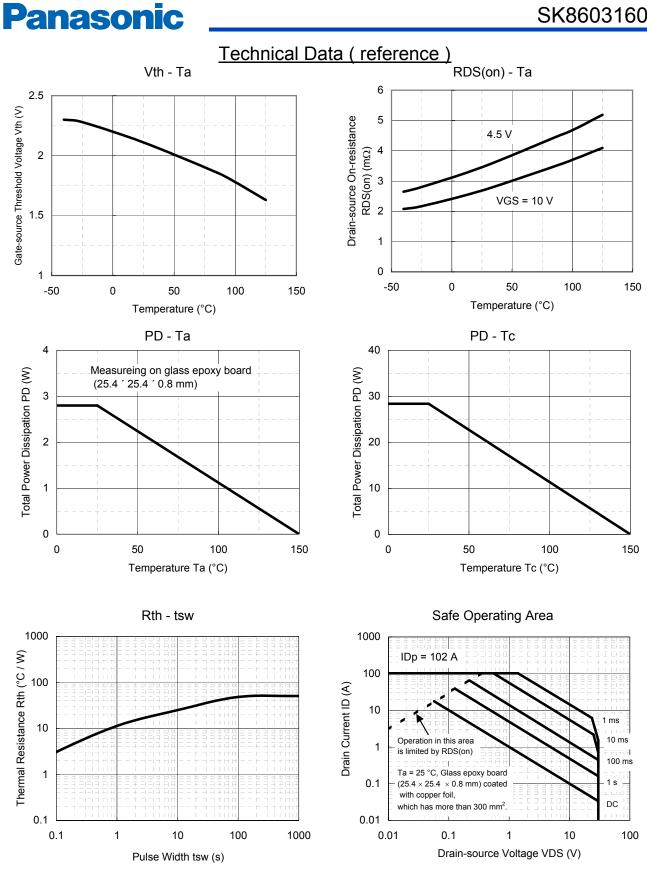
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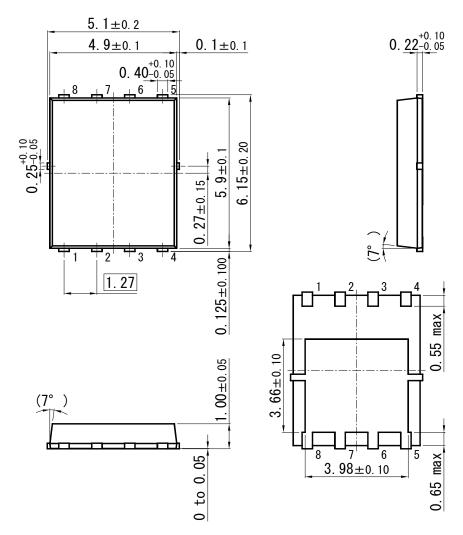


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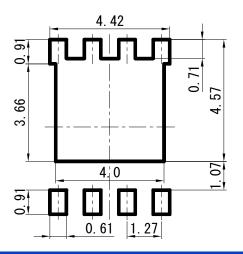


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HSO8-F4-B



Land Pattern (Reference) (Unit : mm)



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